Session 43: New Techniques in Test Generation
Chair: Sandip Kundu

New advances in test generation are needed to handle the ever increasing size of circuits. In this session several novel search pruning techniques are presented. Another highlight of this session is a portable parallel test generator.

43.1 SEQUENTIAL CIRCUIT TEST GENERATION IN A GENETIC ALGORITHM FRAMEWORK
Elizabeth M. Rudnick, Janak H. Patel, Gary S. Greenstein, Thomas M. Niermann

43.2 DYNAMIC SEARCH-SPACE PRUNING TECHNIQUES IN PATH SENSITIZATION
João P. Marques Silva, Karem A. Sakallah

43.3 FUNCTIONAL TEST GENERATION FOR FSMS BY FAULT EXTRACTION
Bapiraju Vinnakota, Jason Andrews

43.4 PROPERHITEC: A PORTABLE, PARALLEL, OBJECT-ORIENTED APPROACH TO SEQUENTIAL TEST GENERATION
Steven Parkes, Prithviraj Banerjee, Janak Patel